

30V N-Channel Trench MOSFET(Preliminary)

General Description

- Trench Power technology
- Low R_{DS(ON)}
- Low Gate Charge
- Optimized for fast-switching applications

Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial

Product Summary

$$\begin{split} V_{DS} & 30V \\ I_{D} & (at \ V_{GS} = 10V) & 100A \\ R_{DS(ON)} & (at \ V_{GS} = 10V) & < 3.4 \text{m}\Omega \end{split}$$

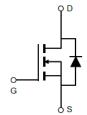
 $R_{DS(ON)}$ (at V_{GS} =4.5V) < 4.5m Ω

100% UIS Tested









Part Number	Package Type	Form	Marking
TTD100N03GT	TO-252	Tape&Reel	100N03GT

Absolute Maximum Ratings (T_A =25°C unless otherwise noted)

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V _{DS}	30	V
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current B	T _C =25°C],	46	۸
	T _C =100°C	l _D	46	Α
Pulsed Drain Current ^A		I _{DM}	300	Α
Avalanche Current A		I _{AS}	27.6	Α
Single Pulse Avalanche Energy L =0.3mH A		E _{AS}	114.3	mJ
Power Dissipation ^C	T _C =25°C	D.	80	W
	T _C =100°C	- P _D	32	W
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 175	°C

Thermal Characteristics

Parameter		Symbol	Maximum	Units
Maximum Junction-to-Case	Steady-State	$R_{\Theta JC}$	1.32	00.444
Maximum Junction-to-Ambient	Steady-State	R _{eJA}	100	°C/W



		Conditions		Value			
Symbol	Parameter			Min	Тур	Max	Units
STATIC P	ARAMETERS	•			•	•	
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA,V _{GS} =0V		30			V
_		$V_{DS} = 30V, V_{GS} = 0V$ $T_{J} = 25^{\circ}C$ $T_{J} = 100^{\circ}C$			1	_	
I _{DSS}	Zero Gate Voltage Drain Current		T _J =100°C			25	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$,			±100	nA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1	1.7	2.4	V
	Otatia Basia Osama On Basiatana	V _{GS} =10V, I _D =20A			2.6	3.4	mΩ
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =4.5V, I _D =20A			3.5	4.5	mΩ
g _{FS}	Forward Transconductance	V _{DS} =10V, I _D =20A			16.8		S
V_{SD}	Diode Forward Voltage	I _S =30A, V _{GS} =0V				1	V
Is	I _S Maximum Body-Diode Continuous Current ^B					46	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance	$V_{GS} = 0V, V_{DS} = 15V, f = 1MH_Z$			3842		
C _{oss}	Output Capacitance				1276		pF
C _{rss}	Reverse Transfer Capacitance				814		
SWITCHI	NG PARAMETERS						
Q _g (10V)	Total Gate Charge	V _{GS} =10V,V _{DS} =15V, I _D =50A			77		
Q_{gs}	Gate Source Charge				9		nC
Q_{gd}	Gate Drain Charge				17		
t _{D(on)}	Turn-On Delay Time	$V_{GS} = 10V, V_{DS} = 15V, I_{D} = 50A,$ $R_{G} = 3\Omega$			13		
t _r	Turn-On Rise Time				12		ns
$T_{D(off)}$	Turn-Off Delay Time				43		
t _f	Turn-Off Fall Time				19		
t _{rr}	Body Diode Reverse Recovery Time	1 -300 4:/4+ 4000/			21		ns
Q _{rr}	Body Diode Reverse Recovery Charge				19		nC

- A. Single pulse width limited by maximum junction temperature.
- B. The maximum current rating is package limited.
- C. The power dissipation P_D is based on $T_{J(MAX)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

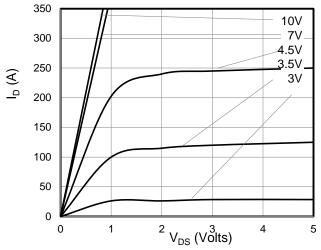


Figure 1: On-Region Characteristics

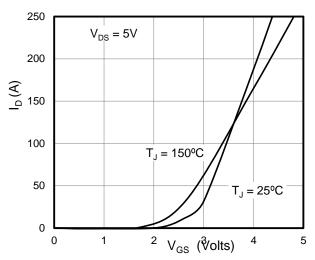


Figure 2: Transfer Characteristics

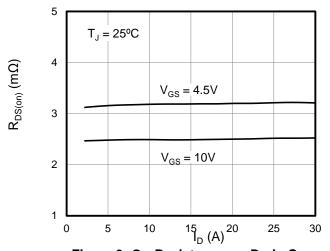


Figure 3: On-Resistance vs. Drain Current

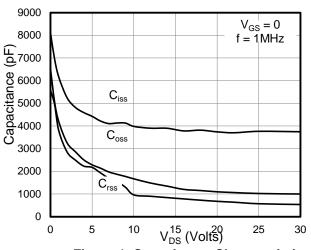


Figure 4: Capacitance Characteristics

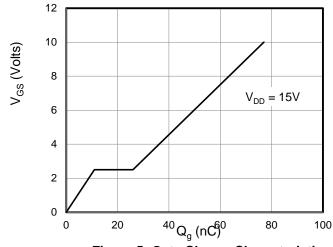


Figure 5: Gate Charge Characteristics

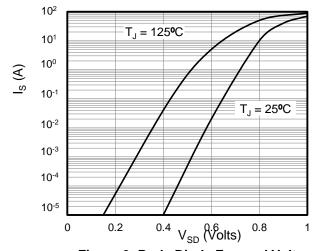
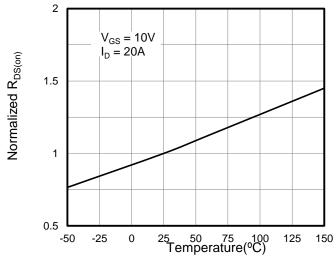


Figure 6: Body Diode Forward Voltage

 $Z_{\theta, JC}$ Normalized Transient Thermal Resistance

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



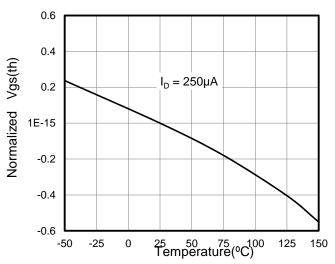
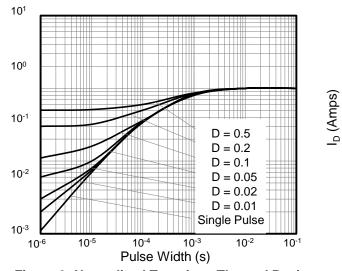


Figure 7: On-Resistance vs. Junction Temperature

Figure 8: Vgs(th) vs. Junction Temperature



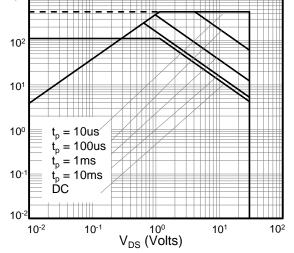


Figure 9: Normalized Transient Thermal Resistance

Figure 10: Safe Operating Area

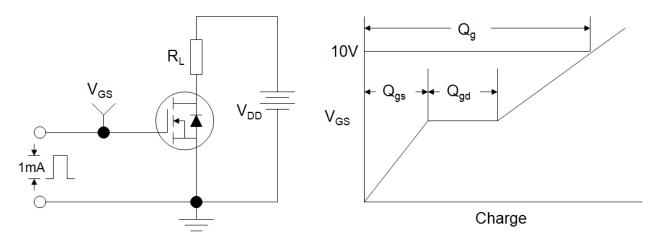


Figure A: Gate Charge Test Circuit and Waveforms

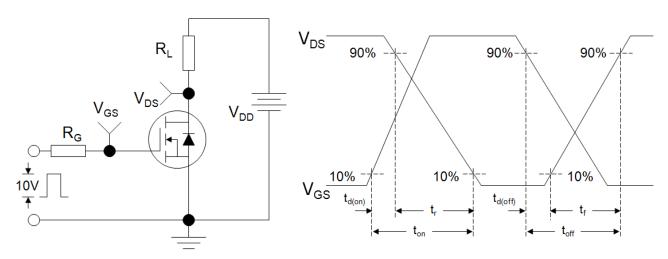


Figure B: Resistive Switching Test Circuit and Waveforms

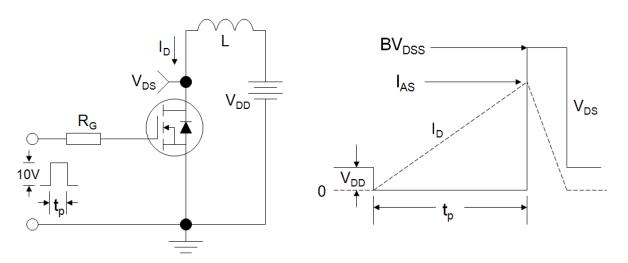
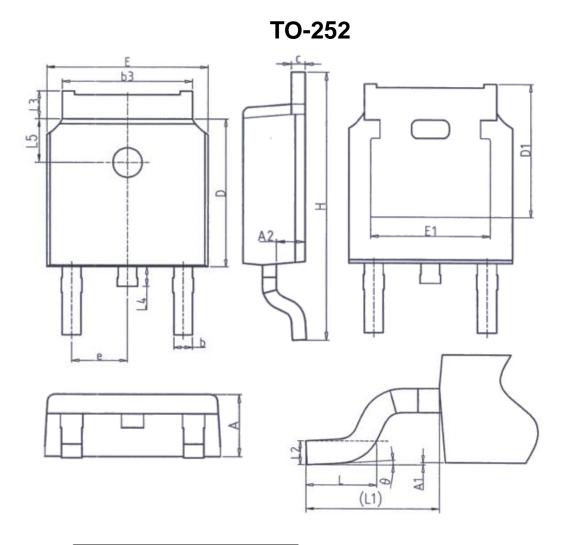


Figure C: Unclamped Inductive Switching (UIS) Test Circuit and Waveforms





Unit: mm			
Symbol	Min.	Max.	
Α	2. 20	2. 40	
A1	0.00	0. 20	
A2	0. 97	1. 17	
b	0. 68	0. 90	
b3	5. 20	5. 50	
С	0. 43	0. 63	
D	5. 98	6. 22	
D1	5. 30REF		
E	6. 40	6. 80	
E1	4. 63	_	

Unit: mm			
Symbol	Min.	Max.	
е	2. 286BSC		
Н	9. 40	10.50	
L	1. 38	1. 75	
L1	2. 90REF		
L2	0. 51BSC		
L3	0.88	1. 28	
L4	_	1.00	
L5	1. 65	1. 95	
θ	0°	8°	



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